

Search Notes

Application/Control No.

10/764,606

Examiner

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Applicant(s)/Patent under
Reexamination

SHIMIZU ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	24	7/26/2006	BT
216	26	7/26/2006	BT
216	96	7/26/2006	BT
216	97	7/26/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
216	24	7/26/2006	BT
216	26	7/26/2006	BT
216	96	7/26/2006	BT
216/97		7/26/2006	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	7/26/2006	BT